

Multi-class classification of independent components of EEG

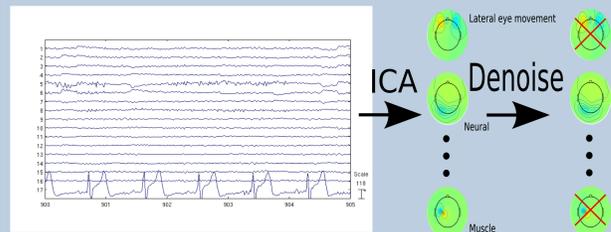
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Introduction

Independent components (ICs) of EEG:

- Patterns of brain activity
- Mutually independent

ICs are used both in preprocessing and analysis of EEG data.



- Classification of ICs is necessary before they can be utilized. However, manual classification is time consuming and subjective.
- Binary classification investigated previously. We look at classification at higher resolution, i.e. into more types of ICs.

Previous work

Neural vs. artifactual classification of ICs

- 2006
LeVan et al.
Tree-augmented naive Bayesian networks used to classify 2s epochs of ICs. Number of epochs of ICs classified as artifactual determine IC classification. Features were mixing matrix, relative band power, dipole fit (fit and residual variance), negentropy, and variance over all channels of each epoch
- 2009
Tangermann et al.
Automatic differentiation between neural and artifactual ICs, comparing LDA to SVM. Characteristics of scalp maps and temporal and frequency characteristics of IC activation over time used as features.
- Viola et al.**
Correlation between spatial maps, i.e. mixing matrices, to classify ICs
- 2010
Mognon et al.
Automatic differentiation between neural and artifactual ICs, using GMM. Features mostly from scalp map, a few temporal from IC activation time series.
- Bartels et al.**
SVM used to classify ICs from 7s epochs. Features consisted of mixing matrix, power in 5Hz wide bins from 0 to 50 Hz, and 6th order AR coefficients. BSS algorithm "Infomax" used to find EMG ICs and "AMUSE" to find EOG ICs.
- 2011
Winkler et al.
Addition and elaboration on the work described in Tangermann et al's 2009 paper.

References

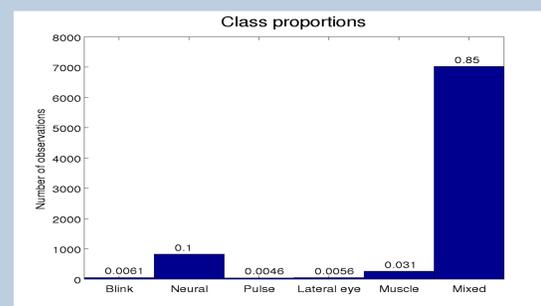
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Data

Data with manually labelled ICs were made available by Julie Onton and Klaus Gramann [6, 3].

Data	Subjects	Channels	Reference	ICA algorithm
[6]	35	250	Active reference	Extended infomax (<i>binica</i> in EEGLab)
[3]	12	64	Referenced to Cz, re-referenced to linked mastoids	Infomax, Brain Vision Analyzer [2]

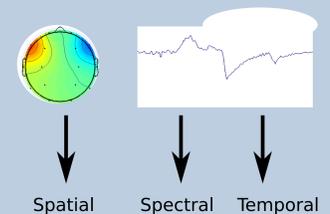
8229 ICs in total in data sets. Types of ICs and class proportions:



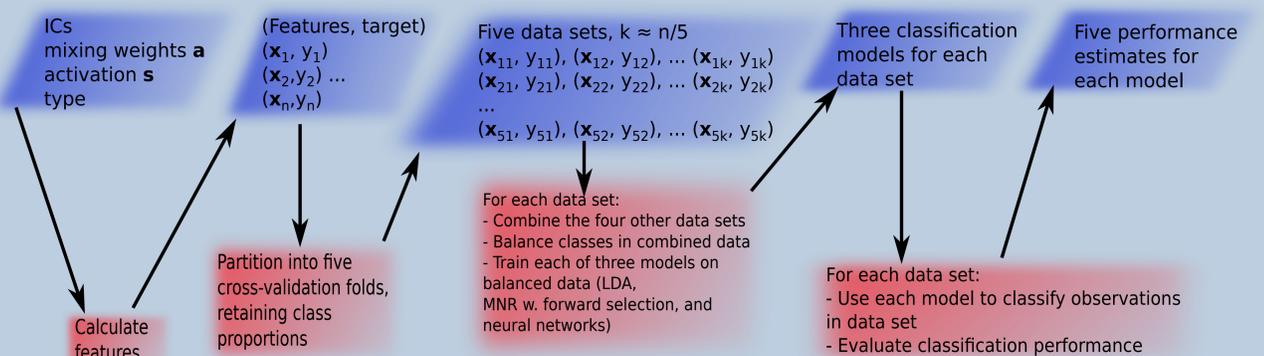
Methods

Features

- 43 features, including most from two previous studies on binary classification [5, 9]
- Features quantify spectral, spatial, and temporal properties of ICs



Classification



Results

	Linear discriminant analysis Classification rate: 0.732						Multinomial regression, forward selection Classification rate: 0.682						Neural network Classification rate: 0.727					
True class	Blink	Neural	Pulse	Lateral eye	Muscle	Mixed	Blink	Neural	Pulse	Lateral eye	Muscle	Mixed	Blink	Neural	Pulse	Lateral eye	Muscle	Mixed
Blink	0.98 ±0.03	0	0	0	0	0.014 ±0	0.97 ±0.04	0.011 ±0.03	0	0	0.017 ±0.04	0	1 ±0	0	0	0	0	0
Neural	0.027 ±0.02	0.88 ±0.04	0.01 ±0.01	0.0072 ±0.003	0.021 ±0.01	0.048 ±0.02	0.077 ±0.02	0.79 ±0.07	0.014 ±0.001	0.0058 ±0.007	0.025 ±0.02	0.066 ±0.07	0.0074 ±0.007	0.91 ±0.02	0.0081 ±0.004	0.0022 ±0.003	0.024 ±0.009	0.046 ±0.02
Pulse	0.04 ±0.03	0.06 ±0.03	1.8 ±0.2	0	0	0	0.14 ±0.2	0.13 ±0.09	0.73 ±0.1	0	0	0	0	0.04 ±0.03	0.96 ±0.03	0	0	0
Lateral eye	0	0	0	1 ±0	0	0	0.18 ±0.3	0.075 ±0.2	0.025 ±0.06	0.75 ±0.3	0	0	0	0	0	1 ±0	0	0
Muscle	0.039 ±0.03	0.02 ±0.03	0.0032 ±0.02	0.034 ±0.03	0.72 ±0.05	0.18 ±0.07	0.032 ±0.06	0.016 ±0.01	0.015 ±0.01	0.061 ±0.07	0.67 ±0.1	0.15 ±0.1	0.0073 ±0.02	0.025 ±0.02	0.0041 ±0.003	0.025 ±0.03	0.76 ±0.04	0.18 ±0.04
Mixed	0.022 ±0.01	0.064 ±0.03	0.019 ±0.02	0.014 ±0.01	0.18 ±0.02	0.71 ±0.03	0.032 ±0.01	0.072 ±0.02	0.024 ±0.01	0.021 ±0.01	0.18 ±0.04	0.67 ±0.03	0.018 ±0.014	0.077 ±0.02	0.016 ±0.005	0.015 ±0.014	0.18 ±0.04	0.7 ±0.04

Conclusions

- Differentiation between multiple classes of ICs is possible
- Classes are linearly separable
- Classification generalizes across studies, electrode setup, and ICA algorithm
- Classification at higher resolution useful for
 - Monitoring of artifact types, possible to instruct subject to minimize certain artifacts
 - Artifacts could be informative, e.g. eye artifacts and drowsiness
 - Classification of non-artifactual types of ICs may be possible

Future work

- Use developed features and classification methods to investigate classification of general types of ICs
- Incorporate the classification scheme into an automatic data cleaning tool